Erratum: Shear strain alters the structure and migration mechanism of self-interstitial atoms in copper [Phys. Rev. Materials 6, 053605 (2022)]

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The error occurs in the next-to-last paragraph of Sec. II (Modeling Methods) of the paper in question. The erroneous statement reads:

"The diffusivity thereby obtained is the SIA diffusivity, not the self-diffusivity of Cu, because G_{MSD} is computed on a per-atom basis, and the SIA is the only significant source of atom mobility in the model."

It should instead read:

"The diffusivity thereby obtained is the self-diffusivity of Cu, not the SIA diffusivity, because G_{MSD} is computed on a per-atom basis, and the SIA is the only significant source of atom mobility in the model."

This error does not affect the conclusions of the paper. However, the diffusivities presented in Figs. 4 and 5(b) should be understood to be SIA-mediated self-diffusivities. They may be converted to SIA diffusivities by multiplying them by the number of atoms in the model, i.e., 4951.

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